

Encrypted Array Freeze Dump, Scan Dump and Register Dump – Enabling Debug for External Customers

Major Project Report

*Submitted in fulfillment of the requirements
for the degree of*

Master of Technology
in
Electronics & Communication Engineering
(Embedded Systems)

By

Juhi Pabuwal
(13MECE07)



Electronics & Communication Engineering Branch
Electrical Engineering Department
Institute of Technology
Nirma University
Ahmedabad-382 481
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May 2015**

Declaration

This is to certify that

- a. The thesis comprises my original work towards the degree of Master of Technology in Embedded Systems at Nirma University and has not been submitted elsewhere for a degree.
- b. Due acknowledgment has been made in the text to all other material used.

- Juhi Pabuwal

13MECE07

Disclaimer

“The content of this paper does not represent the technology, opinions, beliefs, or positions of Intel India Technology Private Limited, its employees, vendors, customers, or associates”



Certificate

This is to certify that the Major Project entitled “**Encrypted Array Freeze Dump, Scan Dump and Register Dump – Enabling Debug for External Customers** ” submitted by **Juhi Pabuwal (13MECE07)**, towards the partial fulfillment of the requirements for the degree of Master of Technology in Embedded Systems, Nirma University, Ahmedabad is the record of work carried out by her under our supervision and guidance. In our opinion, the submitted work has reached a level required for being accepted for examination. The results embodied in this major project, to the best of our knowledge, haven't been submitted to any other university or institution for award of any degree or diploma.

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- Juhi Pabuwal

13MECE07

Abstract

Design for Debugging (DFD) and Design for Testing (DFT) are two designing techniques which add certain testability features to microelectronic design. The goal of debugging is not simply to determine that the chip is not working, but to find out why it is not working. DFD is basically derived from DFT and is used for debugging now days.

Till now Intel customers dont have much debug visibility in microprocessor. Customers need to call Intel Engineers for debugging at the time of error and Intel Engineers will go to customer site and solve the error issue. But now a design is made for extracting data by customers which would facilitate quicker triage of fast escalating customer issues and decreases the turn-around time for debugging. This new component is called as Validation Control Unit (VCU) which is added to provide limited access to data extraction by customers. Customer can collect some information and then pass it on to Intel for re-resolution.

Thesis contain a method which describes how to extract data/values using VCU. At the base level, a controller, named as VCU, is integrated that abstracts low level details of the hardware for debugging. In addition, the abstraction layer through an interface, such as APIs, provides services, routines, and data structures to higher-level software/presentation layers, which are able to collect test data for validation and debug of a platform under test. Moreover, VCU provides secure access to the test architecture.

Thesis contain description of hardware used for debugging. These are connected between host and platform for data extraction. The data which is dumped for debugging contains register values, array values and scan chain values. The project is intended towards validating the data extracted using VCU via JTAG. The encrypted array dump tool allows the customer to extract internal array and debug scan chains along with the exposed registers without having an Intel engineer involved. However, to protect IP, the data they are able to extract will be encrypted and requires an Intel engineer to decrypt and evaluate it

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Abbreviation Notation and Nomenclature

PSV	Post Silicon Validation
DFT	Design For Testing
RTL	Register Transfer Logic
DFD	Design For Debugging
CUD	Circuit Under Debug
EDS	External Design Specification
IP	Intellectual Property
VCU	Validation Control Unit
API	Application Peripheral Interface
AFD	Array Freeze Dump
ITP	In Target Probe
PECI	Platform Environment Control Interface
JTAG	Joint Test Access Group
LDAT	Local Data Access Test
DMI	Direct Media Interface
PCU	Power Control Unit

Chapter 1

Introduction

1.1 Postsilicon Validation

Validation techniques may be classified as pre-silicon and post-silicon. Throughout the pre-silicon method, styles are tested by engineers in a very virtual surroundings with difficult simulation, emulation and formal verification tools. However, in post-silicon validation tests occur on actual devices that runs at real speed once deployed in industrial, real-world system boards using logic analyser and assertion-based tools. Presilicon validation is finished on a RTL machine or emulator and has been the first technique which is successfully utilized by variety of business makers. Once the primary element is prepared, post-silicon validation is finished in a system surroundings to get rid of bugs that can not be detected in presilicon validation due to slow simulation speed that prevents running an out -sized number of tests, tests not run in a particular mode, innovations in circuit technology, and lots of things. Typical postsilicon errors are from interactions between totally different elements. The goal of postsilicon validation is to form certain that no bugs are delievered to consumers and to confirm that the chips meet its specification. Postsilicon validation (PSV) is required to demonstrate that the enforced circuit meets its supposed

behavior.

1.2 Design For Debug

Due to lack of in system controllability and observability, DFD hardware is deployed to support post-silicon validation which helps in accessing internal signals in system that is one of the main challenges to PSV. Variety of solutions are planned to implement the design-for-debug hardware. DFD hardware is employed to rectify the system. DFD hardware is inserted into the planning to assemble the maximum amount knowledge from the CUD so as to know the character of the error[2]. At the time of error in the system, register dump, array freeze dump (AFD) and scan dump are the important information which need to be accessed and look into for debugging.

1.3 Motivation

Post silicon validation is very important part in validation of processors/servers. Responsibility of post silicon validation team does not end up after selling the servers/chip to customers. At the time of error scenarios, Intel Engineers need to go to customer site to collect data and then come back to Intel site for debugging. This is a long procedure. So, a microcontroller unit is added which would facilitate quicker triage of fast escalating customer issues and decreases the turn-around time for debugging. With the help of this validation unit, customer can dump data in different error scenarios and pass it to the Intel engineers. This unit will provide encrypted data which is important for confidentiality of the company. This thesis provides debugging facility which will work on future technologies as well. The project will help in reducing the turn around time for debugging.

1.4 Objective

Till now Intel customers dont have much debug visibility in microprocessor. Customers have to every time call Intel for debugging and Intel Engineers will go and solve the issue. Now, a new component called Validation Control Unit (VCU) is added for providing limited debug access to customers. Customer can collect encrypted information and then pass it on to Intel for re-solution. VCU is included to provide control of and access to design for test features. This is microcontroller based unit. API is run to talk to VCU for accessing information according to a security level. Security level is defined in a way that the customers will not be able to access all the information but only the information which Intel wants customer to see. In short, a limited access to information is given using VCU.

1.5 Broadwell Server

The platform used for thesis is Broadwell server with multiple cores and sockets. Broadwell is the codename for the Intel processor family that is the successor to the Haswell processor family and will be built on Intels 14nm manufacturing process. Most Broadwell products are targeted at the 2 in 1 tablets and notebooks but there will also be versions for desktop and server platforms. Broadwell delivers significant performance advancements over the prior generation, including power efficiency and security. Broadwell DE, EP and EX are different variants of Broadwell server.

Broadwell-DE processors are designed for low power servers. The latest Intel Xeon processors take performance, energy-efficiency and compute density to new heights, while delivering best-in-class support for virtualization, cloud computing, in-memory computing, big-data analytics and technical computing. Servers based on these pro-

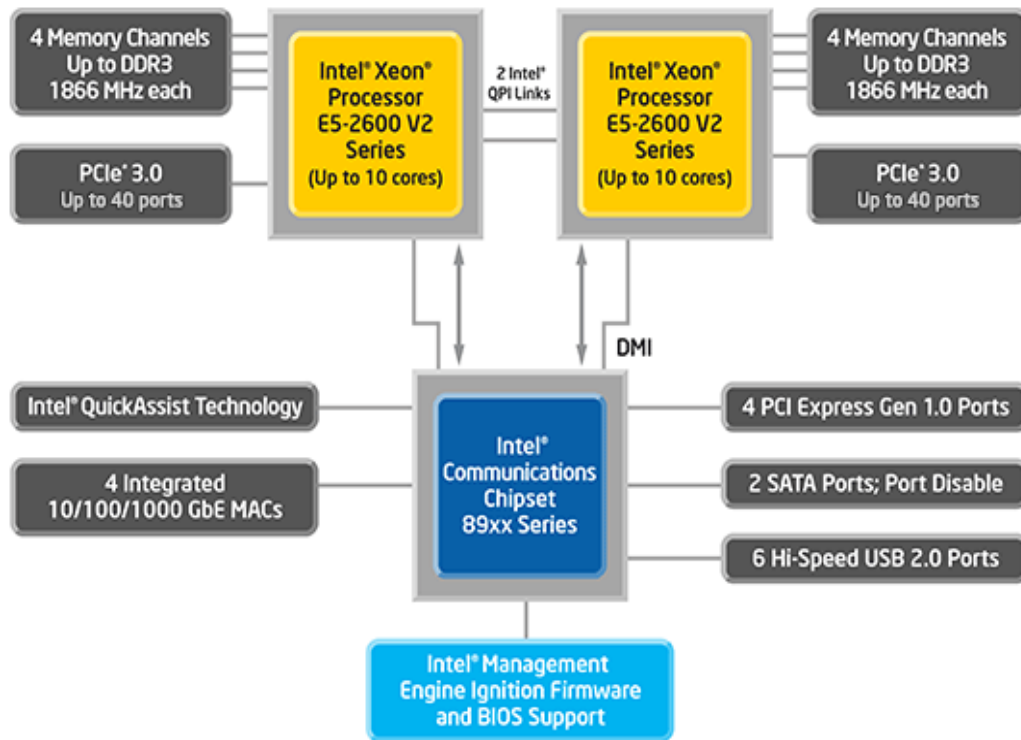


Figure 1.1: Block Diagram of Server
[7]

processors The latest Intel Xeon processors take performance, energy-efficiency and compute density to new heights and deliver best-in-class support for virtualization, cloud computing, in-memory computing, big-data analytics and technical computing. Servers supported by these processors provide the foundation for a standardized, efficient and agile data center that can help to drive down space, power, cooling and management costs, while providing exceptional performance and reliability across the full range of workloads.[6]. New server Xeon microprocessors can feature up to 8 cores with 12 MB L3 cache. The cores support Intels Hyper-Threading, Turbo Boost, virtualization and Trusted Execution technologies. A new feature known as

Processor Trace will be included in Xeon D which will allow capturing details of code execution, supervisor mode access prevention and extensions to ADC instruction.

1.6 Thesis Organization

The rest of the thesis organized as follows.

Chapter 2 explains the different stages of the tool with its background.

Chapter 3 deals with brief description of Validation Control Unit and how API's work.

Chapter 4 gives description ITP and PECL. It also explains how ITP console works.

Chapter 5 describes what is array freeze dump, scan dump and register dump. It also explains the steps used to access these dumps.

Chapter 6 describes the work done with the result.

Chapter 7 concludes what is the output of whole project.

1.7 Summary

This chapter gives the background details of the thesis with the motivation and objective in detail. This chapter also gives details of the server on which the project is tested. The thesis organization gives the brief of every chapter.

Chapter 2

Encrypted AFD and Scan Dump Tool Description

2.1 Background

External debug by the customer requires extracting architectural and hardware state under error conditions. Historically this state has been limited to access to registers exposed in the platform EDS documentation and in a few cases exposure of internal outstanding request buffers. Internal debug teams have access to all of the registers which include those not exposed to customers, all internal arrays, debug scan flops, internal trace data, and all internal flop state. If a customer is unable to root cause their issue with the state extraction mechanisms at their disposal, they contact Intel teams to use the internal debug tools to extract the information they need. Running internal tools to customer systems at remote customer sites slows down the customer debug throughput and puts a burden on the Intel teams needed to arrange the tool attachment and running the tool itself. So, the tool is needed to do all things faster and efficient way. The encrypted array dump tool allows the customer to extract internal array and debug scan chains along with the exposed

registers without having an Intel engineer involved. However, to protect IP, the data they are able to extract will be encrypted and requires an Intel engineer to decrypt and evaluate it. The capability to extract the array and scanout data on their own represents an important improvement in debug throughput. The tool will extract data into a format that will be compatible with the internal debug toolset so all internal tools will be able to operate on the captured information as if it were captured using internal tools vs the customer scripts. As shown in figure 2.1, the unlocked ITP flow is the one which was done previously but after the eAFD tool developed the flow changes to eAFD tool flow.

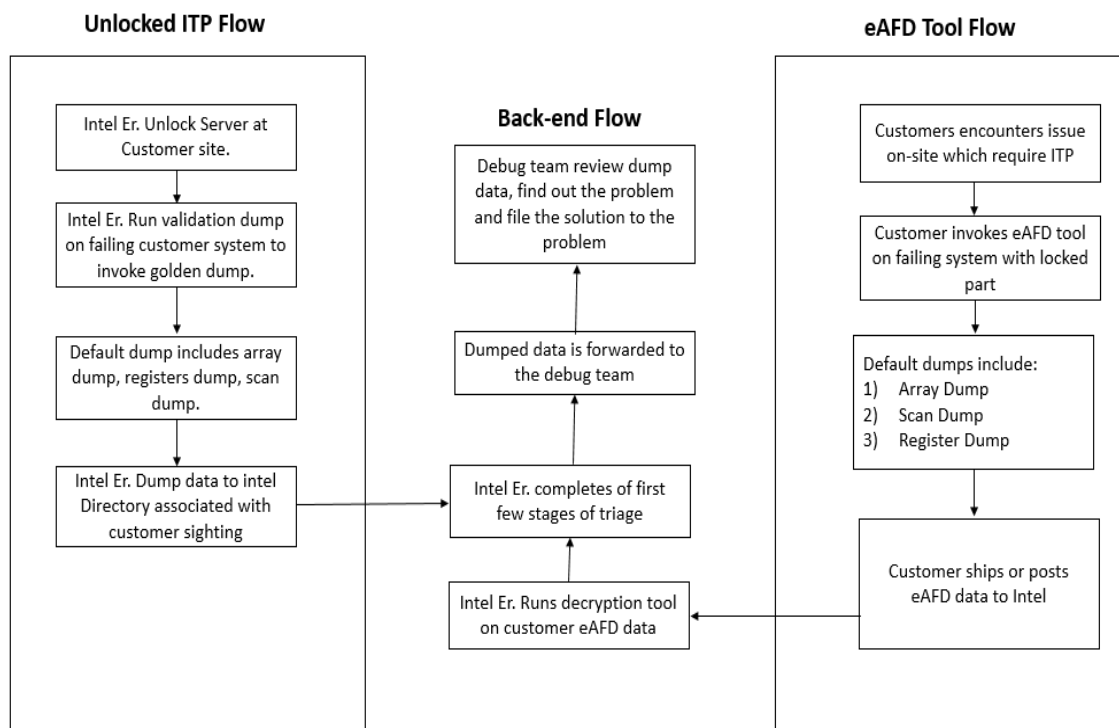


Figure 2.1: Comparison of Unlocked Flow (Without VCU) and Locked flow (With VCU)

2.2 Tool Description

The encrypted static data extraction tool is Customer Script (CScript) command flow initiated on a Python command layer driving an ITP connected via JTAG to a platform. Many of the CScript commands in this flow will themselves call VCU API functions to perform trigger setup, data extraction, and data encryption. This internal toolset is composed of python scripts and processor state definition files needed to tell the script how to extract and decorate the data for each array and scanout chain.

2.3 Tool Flow

There are four stages in tool flow (Figure:2.2):

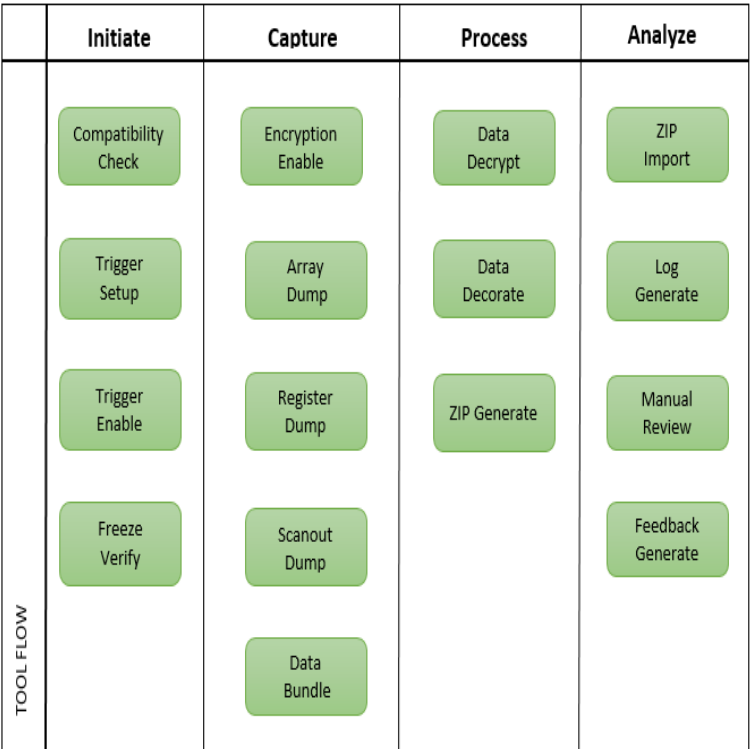


Figure 2.2: Tool Flow

a. **Initiate Stage :** Make sure that the tool has all the resources it needs to run successfully, then setup and trigger a freeze. Steps included in the initiation steps are:

- **Compatibility Check:** It is done by running CScript commands to verify the tool can run successfully and includes checking for software versions, firmware versions, hardware compatibility, and tool connectivity.
- **Trigger Setup:** It is done by running CScript commands to set up all hardware resources properly to ensure a successful trigger and freeze before actually enabling the trigger.
- **Trigger Enable Setup:** It is done by running CScript commands to enable the trigger and freeze actions.
- **Freeze Verify:** It is to verify that the trigger has occurred and the requested arrays and scan agents have frozen.

b. **Capture Stage :** Run the CScript commands to gather information needed for proper processing of the data, then capture and bundle the data to be sent to Intel for processing. Steps included in the capture steps are:

- **Encryption Enable:** Enable encryption is necessary before dumping scan or arrays to secure confidential data.
- **Array Dump:** Dump requested array data or all arrays.
- **Register Dump:** Run CScript commands to dump all available registers.
- **Scanout Dump:** Dump all scan chain data.
- **Data Bundle:** Bundle all of the above encrypted data into a format required for proper processing at Intel.

c. **Process Stage :** Decrypt the bundled data and processes into a format that can be imported into the internal toolset. Steps included in the process steps are:

- **Data Decrypt:** Uses a utility to decrypt the scan and array data.
- **Data Decorate:** Uses a utility that uses the definition files to generate internal tool importable data from the decrypted scan and array data.
- **Zip Generate:** Uses a utility to generate zip files from the register dumps and decorated scan and array data into a format that can be imported directly into internal tool for analysing.

d. **Analyze Stage :** Import the debug data into the internal toolset, then analyze the data using internal log generators such as watch windows, debug scripts, and manual debug methodologies. Based on the debug results, generate feedback guidance to be submitted back to the customer. Steps included in the analyze steps are:

- **Zip Import:** Zip file processed in the process stage is imported into internal tool.
- **Log Generate:** Use internal toolsets to generate logs which can be used for debugging.
- **Manual Review:** Use internal toolsets to manually inspect the stub model.
- **Feedback Generate:** Generate and deliver debug feedback and recommended next steps based on the analysis.

2.4 Summary

The chapter gives the details of the tool which is used for extraction of array and scan chains. Before and after tool development flow for debugging is also discussed. Description of steps of the eAFD tool is also given.

Chapter 3

Validation Control Unit

The Validation Control Unit (VCU) is intended to facilitate fast and unobtrusive processor validation under various use conditions including power-on and post-silicon debug, survivability, electrical validation, manufacturing, and RAS manageability. It consists of a dedicated on-die microcontroller with associated firmware, ROM, RAM, and an IO space that serves as the interface to the rest of the Server processor device. Software is able to request the VCU to coordinate different validation tasks, such as program various breakpoints, micro breakpoint trigger events, extract stored data, deliver validation information and provide different levels of access [3]. Request is sent to VCU through ITP (In Target Probe) via JTAG or through PECCI (Platform Environment Control Interface) using APIs and console.

3.1 Flow of VCU API working

In figure 3.1, a flow diagram for a method of servicing a request from software which utilizes VCU is illustrated. First of all, a request is generated using an Application Programming Interface (API) in response to executing a software program, such as a test and debug program from a third party vendor. The software program

is written to fulfil the demand specified by the API, such as calling conventions recognized by the API. The API is working as an interface between software and VCU hardware. As an example, code stored in memory of a VCU microcontroller is executed in response to the request. In this scenario, the code stored in the VCU may include libraries, routines, data structures, object classes, protocols, etc. In flow it is mentioned that the API request is executed based on a security level. A VCU may include a number of levels of secure access, each of which allows different levels of access to hardware. For example, each level may be associated with an encrypted passcode. So when the software program begins executing, it may provide a secure passcode to unlock its security level, which designates what features the software program is able to access. Therefore, according to the levels of access predefined by the VCU, the information get dumped into the file.

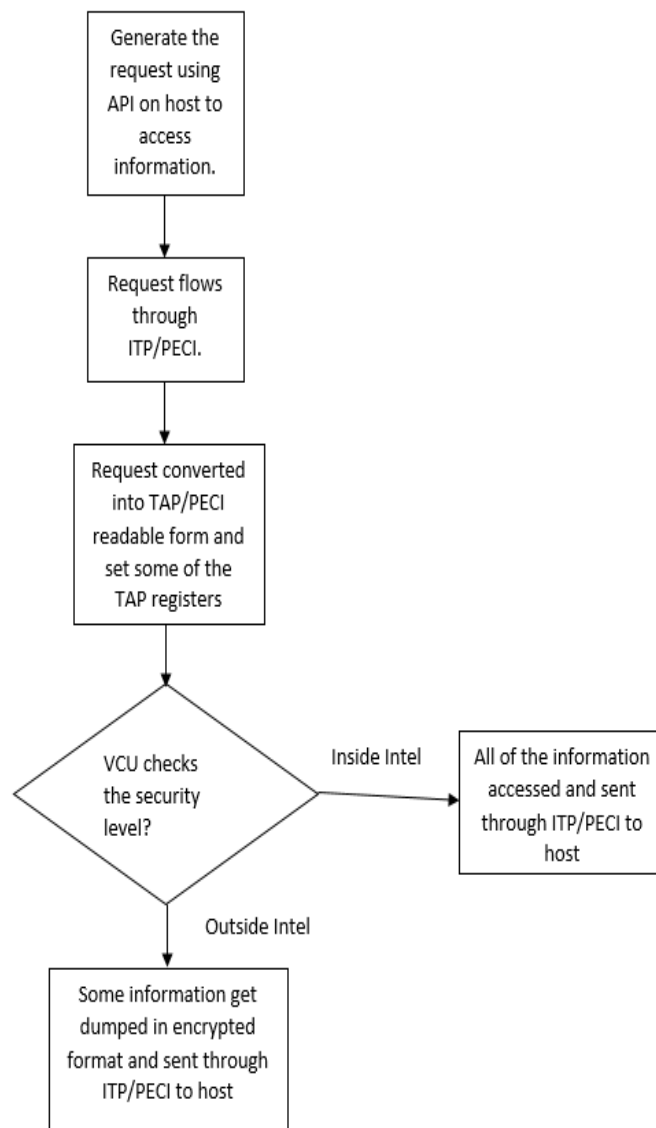


Figure 3.1: Flow of VCU API Working

3.2 VCU API Sequence

Sequence used by VCU API for accessing data are (Figure 3.2):

- a. Opening of sequence with a predefined value to tell VCU that process of reading of array/writing into registers is going to start.
- b. Parameters are set which will tell which array to read, how many bits of array to read etc.
- c. Reading of data is done using the function predefined in the library
- d. Closing of sequence which will tell reading is finished.

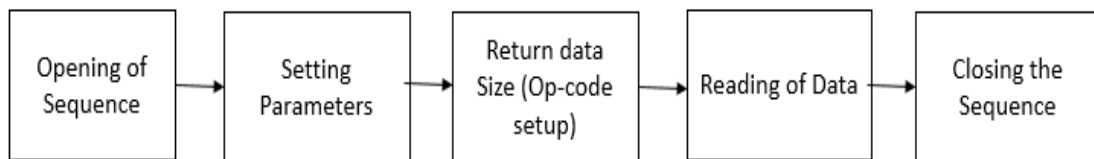


Figure 3.2: VCU API Sequence

3.3 Summary

This chapter describes the main unit (VCU) used for extracting data in encrypted form to protect Intel IP. The flow of how VCU works is also described. VCU API Sequence which every function of VCU script follow is also given.

Chapter 4

In Target Probe and Platform Environment Control Interface

4.1 In Target Probe (ITP)

Standard software debuggers are attached to a running process and can stop execution at any point. After halting the process, instructions, their memory locations, and data currently stored in variables can be looked at. An In-Target Probe (ITP)(4.1) is a hardware device that stops the processor and provides visibility to things like registers and variable values. It's a costly piece of hardware but permits to see at several things on the processor and motherboard. ITPs are generally used to debug hardware (processors and motherboards).ITP is a device attached to computer hardware and microprocessor design to regulate a target chip or similar ASIC at the register level. It typically permits full control of the target device and permits the engineer to access to individual processor registers, program counter and instructions among the device. It permits the processor to set breakpoints.ITP is completely different from In Circuit emulator (ICE) as ITP uses the target device to execute instead of substituting for the target device.



Figure 4.1: ITP with Cables

The ITP is a specialised JTAG master that interfaces into chipsets through a rigorously routed non-public scan chain on the target system. The first operations of the ITP is to provide system interface, execution interface and JTAG interface to the target system. The system interface tells the tool for debug if power, clock and access state are available in the target system. The execution interface is employed to coordinate debug activities with the present execution state of the agents hooked up to the debug port. The JTAG interface permits for question and editing of registers and state inside the agents hooked up to the scan chain.[4].

In the apparatus related to this thesis, the ITP is connected between host and platform (the target machine) and converts API command coming from host to data understood by JTAG. JTAG pins are attached to VCU, which on receiving commands from JTAG sets registers and do the function of accessing data for debugging (Figure 4.2). There are many components integrated on the platform like PCU, PCIe slots, etc. as shown in figure 4.2.

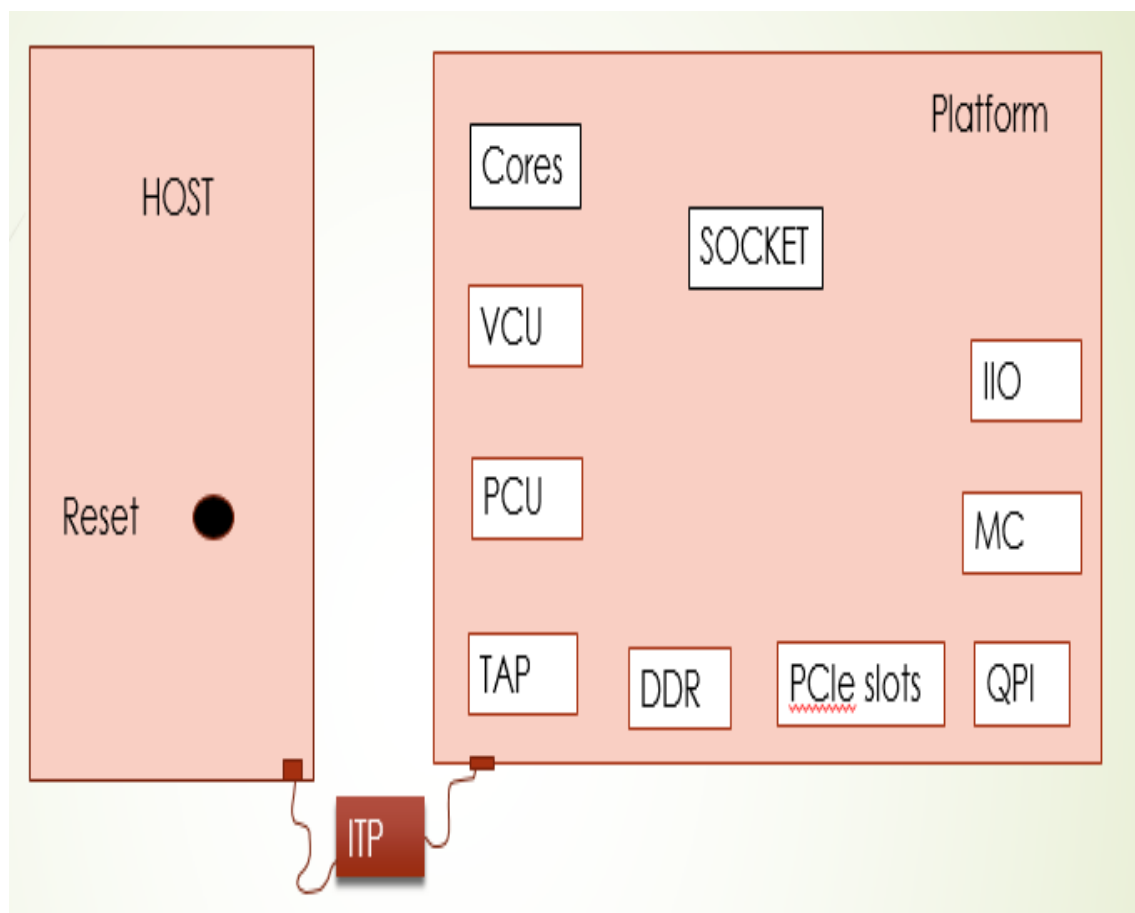


Figure 4.2: Connection between host and platform using ITP

4.2 ITP with Python Console

The console used to send API commands is ITP console which has python features incorporated in it. Figure 4.3 shows the console window used for the thesis to dump the data under different error scenario using JTAG. The API is imported and different parameters are passed to get required data in encrypted form. The property of the console and commands used in the thesis are:

- ITP console uses the interactive mode of python.
- It is easy to import the script and run the function which is written inside the script.
- Script is imported using import function on the interactive prompt of python.
Eg: `import VCU_Script as vcu`
- For calling any function within script use: `script_name.function_name(arguments)`
Eg: in above eg. Script is imported as vcu : `vcu.afd(arguments)`

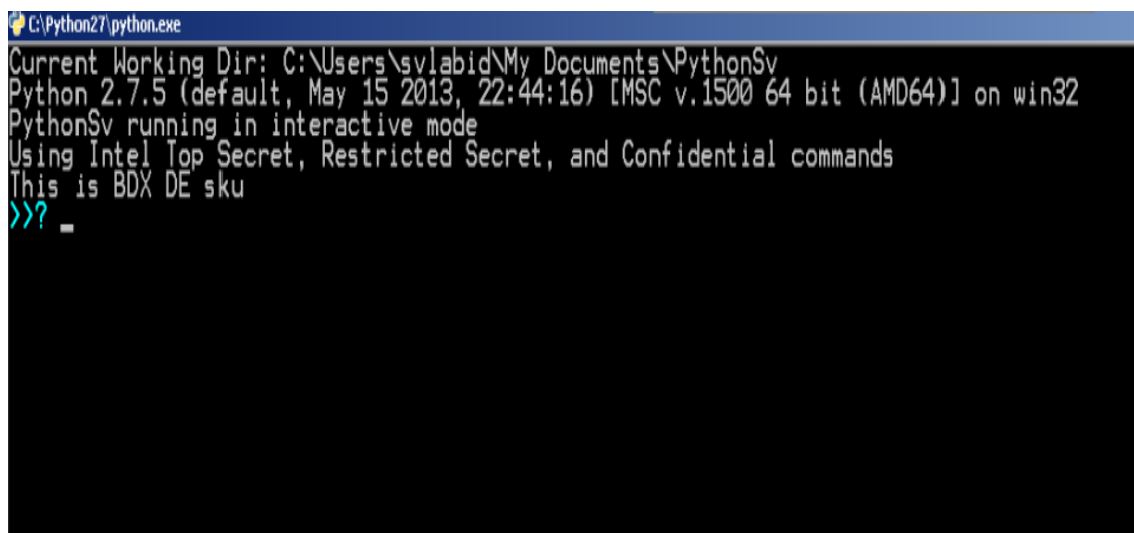


Figure 4.3: ITP Plus Python Console

4.3 Platform Environment Control Interface (PECI)

The PECI is a one-wire interface that provides a communication channel between a PECI client (the processor) and a PECI master (the PCH).

- Supports operation from 2 Kbps to 2 Mbps data transfers.
- Services provided by PECI includes CPU thermal and power information, control functions for power limiting and access to Machine Check registers.

Host talks to PECI through StartDebugger hardware. Commands are send in the same sequence as they are send through ITP to JTAG but here the difference is command are send through StartDebugger to PECI.

PECI is used to access machine check registers with the same VCU sequence as ITP via JTAG is using. It is also validated to access registers after different error scenarios like crash core and Fatal error. The commands used to access registers through PECI are[8]:

- RdPkgConfig() : This command provides read access to the various registers within the processor and returns the data which is specified by index and parameter fields. The index field contains the encoded data for the requested service and is used with the parameter field to specify the exact data being requested. This command returns dword(32bit) data everytime. The response (Responses are data which tells whether the command executed correctly or not) returned with data are different for different scenarios are illustrated in figure 4.4
- WrPkgConfig() : This command provides write access to the within the processor. This command writes data to the processor which is specified by index

and parameter fields. The response returned with data are different for different scenarios are illustrated in figure 4.4

Response	Meaning
Bad Write FCS	Electrical error
Abort FCS	Illegal command formatting
CC: 0x40	Command passed, data is valid.
CC: 0x80	Response timeout. The processor is not able to generate the required response in a timely fashion. Retry is appropriate.
CC: 0x81	Response timeout. The processor is not able to allocate resources for servicing this command at this time. Retry is appropriate.
CC: 0x90	Unknown/Invalid/Illegal Request
CC: 0x91	PECI control hardware, firmware or associated logic error. The processor is unable to process the request.

Figure 4.4: Response after RdPkgConfig() and WrPkgConfig() commands execution

4.4 Summary

This chapter gives the details of the hardware (ITP and PECI) connected between host and platform to access data at the time of error scenario. It also describes in brief how interactive python console helps in debugging and running the scripts with the knowledge of responses if script fails to extract data.

Chapter 5

Data Extraction Steps

Data accesses is done at the time of failures which helps in debugging. There are two ways for accessing data: Internal and External. Internal access is done through directly talking to JTAG/PECI to set value to registers to access/read data without encryption. External access is the access of data in the encrypted form using a controller unit via JTAG/PECI. Dump means accessing a value or dumping the values in a file.

- Array Freeze Dump
- Scan Dump
- Register Dump

5.1 Array Freeze and Dump

Arrays are structures in the RTL. The sizes of array are different for different arrays and mostly all arrays contain information of state. In order to accurately capture array data, the array needs to first be frozen to prevent the data from being modified during the data extraction process. This is known as freezing of array. The

controller registers, named as Local Data Access Test (LDAT) controllers, are set to read data of the arrays. LDAT is directly connected to the arrays. Different set of arrays have different LDAT controllers. To set LDAT controller registers, JTAG (internally) or VCU (externally) can be used. As shown in figure 5.1, every LDAT controller is attached to two or more arrays which shows if we want to dump any data in the array we need to set the particular LDAT controller registers.

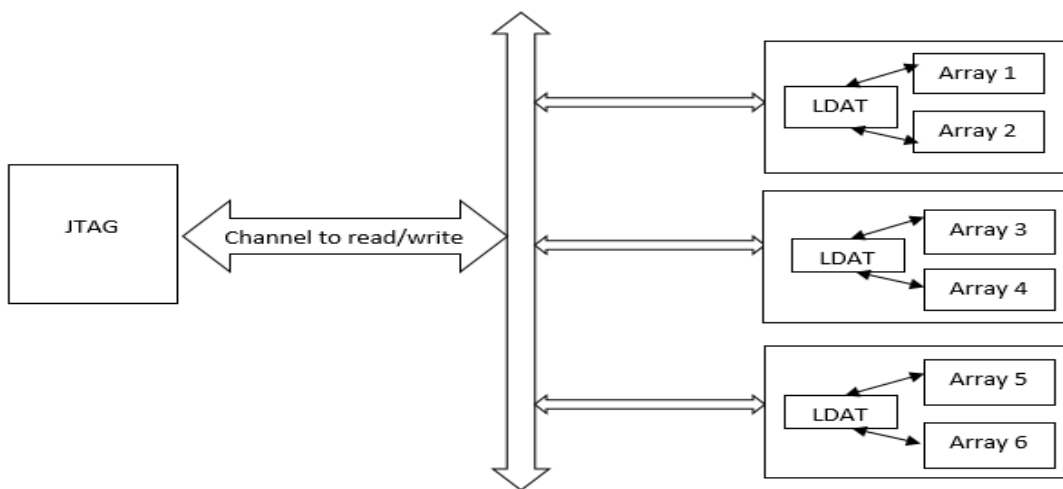


Figure 5.1: Access of array using JTAG

Every array used for debugging responds to a freeze command which is broad-casted in the processor. After receiving this command, write logic of array is disabled immediately which freezes its contents even when the processor clock remains running. There are two ways of freezing the array:

1.) Debug Mode: This mode stops a running processor and places it in an interactive testing mode. After testing operations have been completed, the processor can be released into normal execution mode again[5].

2.) Internal breakpoint mechanism: An internal breakpoint mechanism sets a breakpoint at particular instant which freezes the content of array. This mechanism can be set up to respond to any of a variety of internal micro-architectural events.

5.2 Scan Dump

These are internal flops instantiated in the processor logic to capture state specifically for debug purposes. Scan-out technique provides facility to see data of internal nodes in the design. Scan-out can work in snapshot mode. It takes a single sample of the key processor state, saves it in shadow flip flops and shifts it out through the JTAG port while the processor is running. Shadow flip-flops or latches are used to provide a non-destructive scan out ability that preserves the existing system state. This mode is used while the processor is running at full clock frequency, without disturbing its operation. As shown in figure 5.2, each flip-flop has its shadow flip-flop. When the scan dump command is executed, chain is formed and data get stored in shadow flip flop. The data stored in shadow flip flop is taken out by inserting dummy data in.

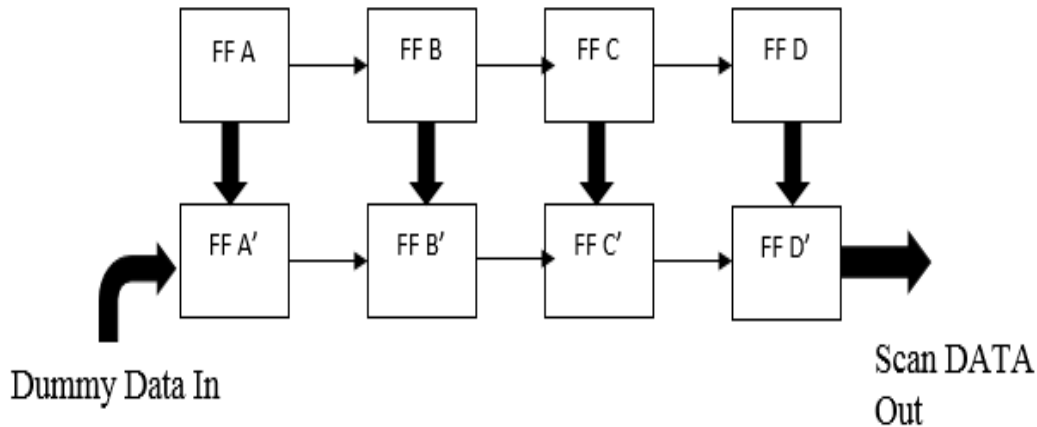


Figure 5.2: Scan Dump

5.3 Register Dump

Some of the registers are exposed to customer as part of the EDS documentation. Register values are important to determine the architectural configuration being applied and to determine what errors are being indicated at the point of failure. The CScripts already have mechanisms to read out these registers as part of their existing functions. Some of them are control registers, memory input output registers and status registers.

5.4 Steps for dumping data

a. Array Freeze Dump:

Encrypted array dump is done using VCU via JTAG through ITP. Scripts are used to set LDAT controller and VCU registers to start array dump after freezing the data in it. CScript is called to start array freeze dump at the time of error. The AFD script is divided into two parts. Following are things done by front-end script (Figure 5.3)(given to customers) :

- (1) One by one array will be taken from the list defined in the script.
- (2) For individual array the repeated steps will be:
 - Freezing using VCU API (breakpoint set)
 - Encryption enabling using VCU API
 - Dump using VCU API
- (3) Wrap all the encrypted dumped data in a zip folder.

Following are things done by back-end script (Figure 5.4)(internal at Intel) :

- (1) Load the zip file into the internal tool for decoration , so that it can be compared easily.
- (2) Decryption of data loaded into the tool.
- (3) Put all the log generated in the file for manual comparison.

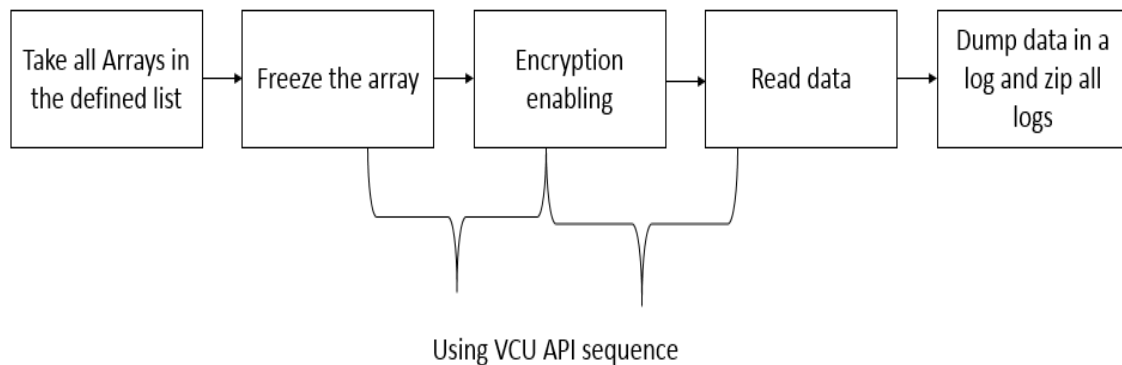


Figure 5.3: Front-end Flow

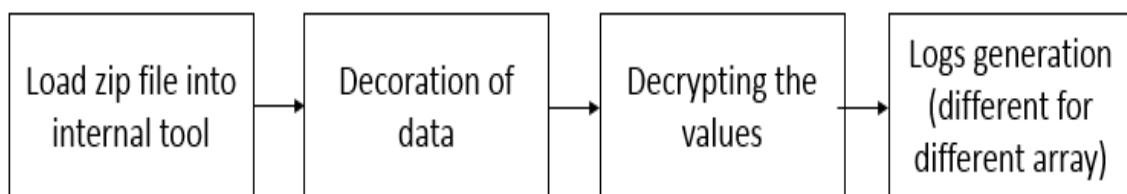


Figure 5.4: Back-end Flow

b. **Scan Dump:**

Steps to implement scan dump through VCU are similar to VCU API sequence of array dump. The registers which are set for scan dump are different from the one which are set for array dump. Linear scan chains are formed for scan dump as shown in figure 5.2. In scan dump first we need to select chains and units which we want to dump and then freeze all chains as shown in figure 5.5.

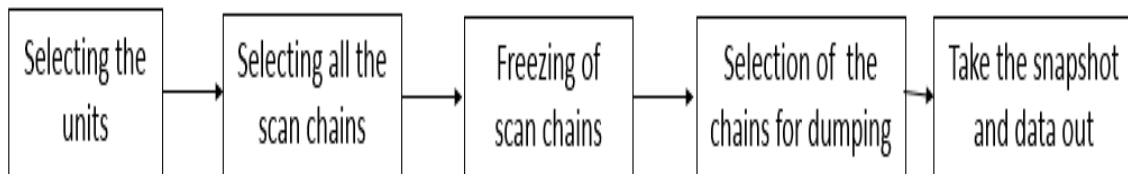


Figure 5.5: Scan Dump

c. **Register Dump:**

Register dump can be done in several ways i.e. can be directly read setting VCU as access or using VCU API.

5.5 Error Scenarios

Several error scenarios are generated to dump data to debug further. Some of the errors are:

- a. **Crash Cores:** When the cores does not respond to any command given by user then crash core error occurs. It happens due to invalid data written into registers or several instruction running simultaneously leading to crash core and hung the system. After core crashes a crash core dump (using VCU API)

is done which consists of the registers in which records the working memory of a computer program when the program has terminated abnormally (crashed). The processor registers which are dumped in the crash core scenario include the program counter and stack pointer, memory management information and other processor and operating system flags and information. Core dumps are used to assist in analyzing and debugging errors in computer programs. Array dump, scan dump and register dump also checked in this scenario for debugging.

- b. **DMI Error Injection:** If there is a break in communication between different components, it is also considered to be an error. In this scenario debugging is done through array, scan and register dump.
- c. **Thermal Error:** When processors get heated up, it halt its operation. Due to some operation which goes to infinite loop the processor gets heated up and error occurs in the system.

5.6 Summary

This chapter includes the work done as the part of the thesis/project. Details of different kinds of data extracted using the VCU in encryption form and validating the data after decryption is given. The steps did for extracting data with block diagrams is also described. The error scenarios in which the array , register and scan data are validated is also described in this chapter.

Chapter 6

Result

The VCU microcontroller assembly coding was already written for reading the data. This thesis is based on writing the script for dumping data through VCU, checking the correctness of encryption and decryption of data and validating the data in different error scenarios. For validation of data knowledge of some basic JTAG commands which can directly access the data without any VCU intervention was important part. This is called to be an internal accessing of data. This data is always correct until unless ITP is not screwed up. External data which is accessed through VCU is compared to this data for validation. If the data matches then VCU API is working perfectly. Parameters are passed in the function defined in the API to tell VCU which data to dump. This data ,as discussed in previous chapters, is dumped in encrypted form in different error scenarios and so can be used for debugging after decryption.

Scripts are written to access array and scan dump data in encrypted form. These scripts are checked under normal conditions and after spoofing different error scenarios. The encrypted data is then decrypted and compared with internal tool. This decrypted data is then compared with the golden values and then analyse for

debugging. The validation of this data is necessary before going further.

Figure 6.1 shows how the VCU API script is imported on Python Console and array dump is done. Figure 6.2 represents the output of array dump after settingg the parameters. Figure 6.3 shows two logs. One of them is taken using the script written for tool and other one is taken using the internal script which uses JTAG directly to access data. Figure 6.4 show the comparison of scan results using VCU with JTAG values.

```
>>> import vcuaPI_bdx as vcu
>>> vcu.seq_start_array_dump(0x80000680, 0x202a000f, 0x00020160, 0x00c00000, 0x01001300, 0x0, 0x0, 0x0, 0x81000000)
{'index': '0x0', 'command': '0x40', 'data': '0x0', 'runbusy': '0x0'}
{'index': '0x0', 'command': '0x40', 'data': '0x0', 'runbusy': '0x0'}
{'index': '0x0', 'command': '0x40', 'data': '0x0', 'runbusy': '0x0'}
{'index': '0x0', 'command': '0x40', 'data': '0x0', 'runbusy': '0x0'}
{'index': '0x0', 'command': '0x40', 'data': '0x0', 'runbusy': '0x0'}
{'index': '0x0', 'command': '0x40', 'data': '0x0', 'runbusy': '0x0'}
{'index': '0x0', 'command': '0x40', 'data': '0x0', 'runbusy': '0x0'}
{'index': '0x0', 'command': '0x40', 'data': '0x0', 'runbusy': '0x0'}
{'index': '0x0', 'command': '0x40', 'data': '0x0', 'runbusy': '0x0'}
{'index': '0x0', 'command': '0x40', 'data': '0x0', 'runbusy': '0x0'}
{'index': '0x0', 'command': '0x40', 'data': '0x28', 'runbusy': '0x0'}
```

Figure 6.1: Importing script and running a function

```

Start reading data....
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x6e8a5e, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x6f663f, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x743a45, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x6d96fc, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x6c6a33, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x65d7c4, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x672455, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x68bbc1, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x664cd9, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x6565a3, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x6e8bd9, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x73f417, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x74fba8, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x74c8a8, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x74fdba, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x74faca, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x74cabd, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x74cabd, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x74fc41, 'runbusy': 0x0'
index: 0x0, command: 0x40, data: 0x0, 'runbusy': 0x0'

```

Figure 6.2: Output data of an array dump after running script

array0_goldenvalue.txt	array0_tool.txt
4/7/2015 7:17:00 PM 393 bytes <default> A P	4/7/2015 7:16:09 PM 393 bytes <default>
socket_number.array_name	socket_number.array_name
Data	Data
00 000040000000	00 000040000000
01 000040000000	01 000040000000
02 00017bc80000	02 00017bc80000
03 000040000000	03 000040000000
04 000179720000	04 000179720000
05 00017bc80000	05 00017bc80000
06 000040000000	06 000040000000
07 00017bd00000	07 00017bd00000
08 000001000000	08 000001000000
09 000001680000	09 000001680000
0A 000163960000	0A 000163960000
0B 000001180000	0B 000001180000
0C 00016dfa0000	0C 00016dfa0000
0D 000166ea0000	0D 000166ea0000
0E 00017fd60000	0E 00017fd60000
0F 0001739e0000	0F 0001739e0000
10 000163240000	10 000163240000
11 0001622a0000	11 0001622a0000
12 000175180000	12 000175180000
13 000179720000	13 000179720000

Figure 6.3: Array Data Comparison - VCU API output with JTAG output

Figure 6.4: Scan Dump Data Comparison - VCU output with Golden Values

Chapter 7

Conclusion

Postsilicon Validation is considered to be an important step in validation of any chip. So, DFD is included as a part of postsilicon validation which helps in debugging the chip even after it has been shipped to customers. This thesis is intended towards giving the visibility to customers for dumping data, at time of error scenarios, which can be used for debugging. As we know providing confidential data to customers may lead to exploitation of the companys IP, so a microcontroller unit is embedded into the design, named as VCU, which will dump the data and take care of the encrypting the data before dumping.

In this project, the script for array freeze, scan dump and register dump is written which helps in extraction data in different error scenarios. These scripts are written and validated with encryption enabled and then decryption of encrypted values. There are two modes: unlocked mode for Intel Engineers and locked mode for customers. These scripts are checked for unlocked mode where data is dumped without encryption. Then checked for locked mode where data is dumped with encryption. The extracted data is matched with the golden values. These scripts are checked for different error scenarios as well. In short correctness of extracted data

using VCU is checked with the validation of proper functioning of encryption and decryption of data.

Now, in the near future the customers can extract internal array and debug scan chains along with the exposed registers without having an Intel engineer involved. However, to protect IP, the data they are able to extract will be encrypted and requires an Intel engineer to decrypt and evaluate it. The capability to extract the array and scanout data on their own represents an important improvement in debug throughput. The tool will extract data into a format that will be compatible with the internal debug toolset. So all internal tools will be able to operate on the captured information.

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